

Notice of References Cited

Application/Control No.

09/532,775

Applicant(s)/Patent Under
Examination
KANO ET AL.

Examiner

Tuan M Nguyen

Art Unit

2828

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,319,742 B1	11-2001	Hayashi et al	438/46
	B	US-6,265,287 B1	07-2001	Tsujimura et al	438/478
	C	US-6,087,681	07-2000	Shakuda	257/103
	D	US-6,242,761 B1	06-2001	Fujimoto et al	257/94
	E	US-6,359,292 B1	03-2002	Sugawara et al	257/103
	F	US-6,185,238 B1	02-2001	Onomura et al	372/46
	G	US-6,111,273	08-2000	Kawai	257/94
	H	US-5,966,396	10-1999	Okazaki et al	372-46
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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